

1. Global joint venture starts operations as WeEn Semiconductors

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WeEn Semiconductors



Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a SOT78D (TO-220AB) internally insulated plastic package intended for use in circuits where high static and dynamic dV/dt and high dl/ dt can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ($T_{j(max)} = 150~^{\circ}$ C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

2. Features and benefits

- 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High junction operating temperature capability (T_{i(max)} = 150 °C)
- High voltage capability
- High current capability
- Less sensitive gate for highest noise immunity
- Internally insulated package
- Internally isolated mounting base
- Triggering in three quadrants only
- Very high immunity to false turn-on by dv/dt and IEC 61000-4-4 fast transient
- Package is RoHS compliant
- Package meets UL94V0 flammability requirement
- Package meets UL1557 isolation test requirement rated at 2500V RMS

3. Applications

- Heating controls
- High power motor control
- High power switching
- Applications subject to high temperature (T_{j(max)} = 150 °C)

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|---------------------------------------|--|-----|-----|-----|------|
| V _{DRM} | repetitive peak off- state voltage | | - | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 86 \text{ °C}$; Fig. 1; Fig. 2; Fig. 3 | - | - | 30 | Α |





| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|--|--|---|------|-----|------|------|
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5 | - | - | 270 | A |
| | | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms | - | - | 297 | A |
| T _j | junction temperature | | - | - | 150 | °C |
| Static char | acteristics | ' | | 1 | 1 | |
| I _{GT} g | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 7}}$ | - | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;}$ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$ | - | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;}$ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$ | - | - | 35 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 50 | mA |
| V_{T} | on-state voltage | I _T = 42 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.2 | 1.55 | V |
| Dynamic cl | haracteristics | | | | ' | - |
| dV _D /dt rate of ris voltage | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 2000 | - | - | V/µs |
| | | V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 1000 | - | - | V/µs |
| dl _{com} /dt | rate of change of commutating current | V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/ μ s; (snubberless condition); gate open circuit | 16 | - | - | A/ms |
| | | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/ μ s; (snubberless condition); gate open circuit | 13 | - | - | A/ms |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-------------------------|--------------------|----------------|
| 1 | T1 | main terminal 1 | mb | T2—T1 |
| 2 | T2 | main terminal 2 | $1 \bigcirc 1$ | Sym051 |
| 3 | G | gate | | , |
| mb | n.c. | mounting base; isolated | | |
| | | | TO-220AB (SOT78D) | |

6. Ordering information

Table 3. Ordering information

| Type number | Package | | | | |
|---------------|----------|---|---------|--|--|
| | Name | Description | Version | | |
| BTA330Y-800CT | TO-220AB | plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 | SOT78D | | |

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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | I N | Min | Max | Unit |
|---------------------|--------------------------------------|---|-----|-----|-------|------|
| V_{DRM} | repetitive peak off-state voltage | | - | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 86 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3 | - | - | 30 | A |
| I _{TSM} | non-repetitive peak on-state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5 | - | - | 270 | A |
| | | full sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 16.7 \text{ms}$ | - | - | 297 | A |
| I ² t | I ² t for fusing | t _p = 10 ms; sine-wave pulse | - | - | 364.5 | A²s |
| dl _T /dt | rate of rise of on-state current | I _G = 70 mA | - | - | 100 | A/µs |
| I _{GM} | peak gate current | | - | - | 2 | Α |
| P_{GM} | peak gate power | | - | _ | 5 | W |
| P _{G(AV)} | average gate power | over any 20 ms period | - | - | 0.5 | W |
| T _{stg} | storage temperature | | - | -40 | 150 | °C |
| Tj | junction temperature | | - | - | 150 | °C |

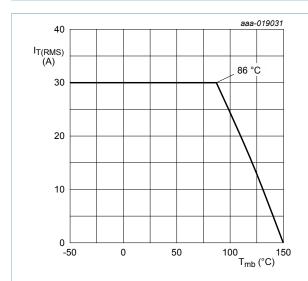
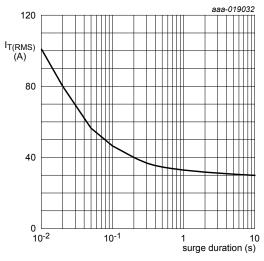


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



f = 50 Hz; T_{mb} = 86 °C

Fig. 2. RMS on-state current as a function of surge duration; maximum values

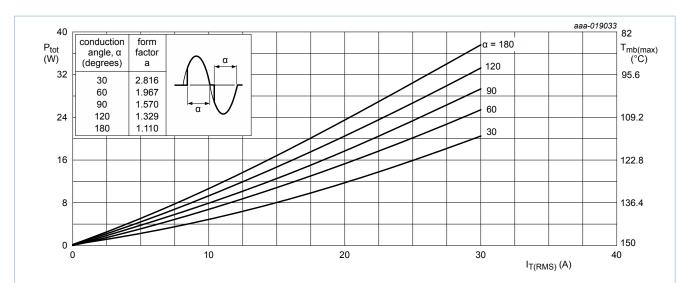


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

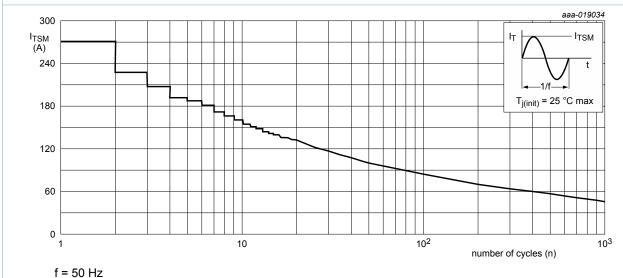
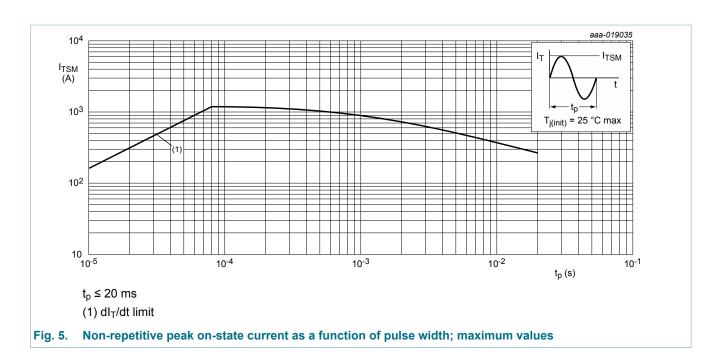


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|--|--------------------|-----|-----|-----|------|
| R _{th(j-mb)} | thermal resistance from junction to mounting base | full cycle; Fig. 6 | - | - | 1.7 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient free air | in free air | - | 60 | - | K/W |

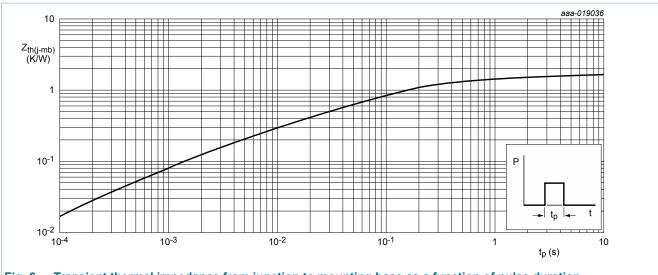


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

9. Isolation characteristics

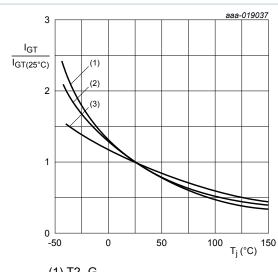
Table 6. Isolation characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------------|-----------------------|--|-----|-----|------|------|
| V _{isol(RMS)} | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz \leq f \leq 60 Hz; RH \leq 65 %; T_{mb} = 25 °C | - | - | 2500 | V |
| C _{isol} | isolation capacitance | from main terminal 2 to external heatsink; f = 1 MHz; T _{mb} = 25 °C | - | 10 | - | pF |

10. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|----------------------------------|---|---|------|------|------|------|
| Static cha | racteristics | 1 | | | | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ G+;$ $T_j = 25 \text{ °C; } Fig. 7$ | - | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$ | - | - | 35 | mA |
| | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 7}}$ | - | - | 35 | mA | |
| I _L latching current | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 70 | mA | |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 80 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 ^{\circ}\text{C}; \underline{\text{Fig. 8}}$ | - | - | 70 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 50 | mA |
| V _T | on-state voltage | I _T = 42 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.2 | 1.55 | V |
| V _{GT} gate | gate trigger voltage | V _D = 12 V; T _j = 25 °C; <u>Fig. 11</u> | - | 0.9 | 1.3 | V |
| | | V _D = 400 V; T _j = 150 °C; <u>Fig. 11</u> | 0.2 | 0.45 | - | V |
| I _D off-state current | off-state current | V _D = 800 V; T _j = 25 °C | - | - | 10 | μΑ |
| | | V _D = 800 V; T _j = 150 °C | - | 0.4 | 2 | mA |
| Dynamic | characteristics | | I | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 2000 | - | - | V/µs |
| | | V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 1000 | - | - | V/µs |
| dI _{com} /dt | rate of change of commutating current | V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/ μ s; (snubberless condition); gate open circuit | 16 | - | - | A/ms |
| | | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 30 A; dV_{com}/dt = 20 V/µs; (snubberless condition); gate open circuit | 13 | - | - | A/ms |



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

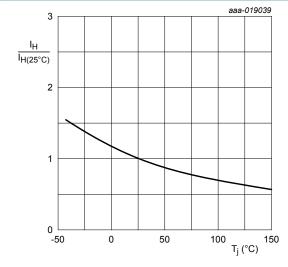


Fig. 9. Normalized holding current as a function of junction temperature

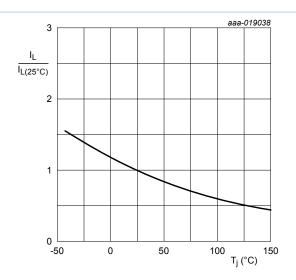
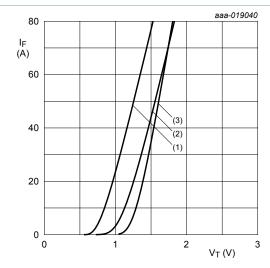
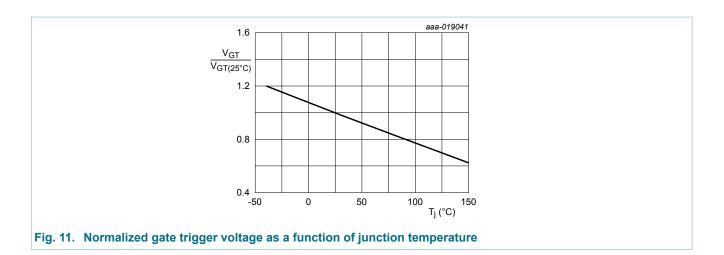


Fig. 8. Normalized latching current as a function of junction temperature



- V_o = 1.066 V; R_s = 0.010 Ω
- (1) T_j = 150 °C; typical values
- (2) T_i = 150 °C; maximum values
- (3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



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11. Package outline

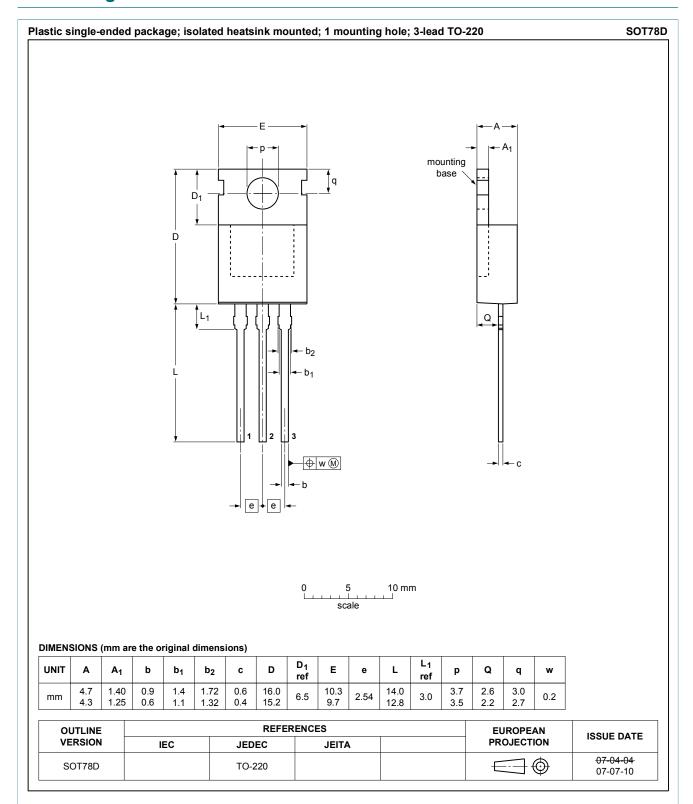


Fig. 12. Package outline TO-220AB (SOT78D)

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|--------------------------------------|--------------------|---|
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| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
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